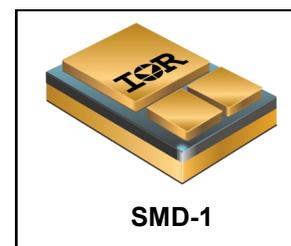


**POWER MOSFET**  
**SURFACE MOUNT(SMD-1)**
**200V, P-CHANNEL**  
**REF: MIL-PRF-19500/595**
**HEXFET<sup>®</sup> MOSFET TECHNOLOGY**
**Product Summary**

Part Number	RDS(on)	I <sub>D</sub>
IRFN9240	0.51Ω	-11A


**Description**

HEXFET<sup>®</sup> MOSFET technology is the key to IR HiRel advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance. HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required. The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.

**Features**

- Simple Drive Requirements
- Hermetically Sealed
- Surface Mount
- Dynamic dv/dt Rating
- Light Weight

**Absolute Maximum Ratings**

Symbol	Parameter	Value	Units
I <sub>D1</sub> @ V <sub>GS</sub> = -10V, T <sub>C</sub> = 25°C	Continuous Drain Current	-11	A
I <sub>D2</sub> @ V <sub>GS</sub> = -10V, T <sub>C</sub> = 100°C	Continuous Drain Current	-7.0	
I <sub>DM</sub> @ T <sub>C</sub> = 25°C	Pulsed Drain Current ①	-44	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Maximum Power Dissipation	125	W
	Linear Derating Factor	1.0	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy ②	500	mJ
I <sub>AR</sub>	Avalanche Current ①	-11	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①	12.5	mJ
dv/dt	Peak Diode Recovery ③	-5.0	V/ns
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to + 150	°C
	Package Mounting Surface Temperature	300 (for 5 S)	
	Weight	2.6 (Typical)	g

For footnotes refer to the page 2.

### Electrical Characteristics @ T<sub>j</sub> = 25°C (Unless Otherwise Specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	-200	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -1.0mA
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	-0.2	—	V/°C	Reference to 25°C, I <sub>D</sub> = -1.0mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	0.51	Ω	V <sub>GS</sub> = -10V, I <sub>D2</sub> = -7.0A ④
		—	—	0.52		V <sub>GS</sub> = -10V, I <sub>D1</sub> = -11A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	-2.0	—	-4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
G <sub>fs</sub>	Forward Transconductance	4.0	—	—	S	V <sub>DS</sub> = -15V, I <sub>D2</sub> = -7.0A ④
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	—	—	-25	μA	V <sub>DS</sub> = -160V, V <sub>GS</sub> = 0V
		—	—	-250		V <sub>DS</sub> = -160V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Leakage Forward	—	—	-100	nA	V <sub>GS</sub> = -20V
	Gate-to-Source Leakage Reverse	—	—	100		V <sub>GS</sub> = 20V
Q <sub>G</sub>	Total Gate Charge	—	—	60	nC	I <sub>D1</sub> = -11A
Q <sub>GS</sub>	Gate-to-Source Charge	—	—	15		V <sub>DS</sub> = -100V
Q <sub>GD</sub>	Gate-to-Drain ('Miller') Charge	—	—	38		V <sub>GS</sub> = -10V
t <sub>d(on)</sub>	Turn-On Delay Time	—	—	35	ns	V <sub>DD</sub> = -100V
t <sub>r</sub>	Rise Time	—	—	85		I <sub>D1</sub> = -11A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	—	85		R <sub>G</sub> = 9.1Ω
t <sub>f</sub>	Fall Time	—	—	65		V <sub>GS</sub> = -10V
L <sub>S</sub> + L <sub>D</sub>	Total Inductance	—	4.0	—	nH	Measured from the center of drain pad to center of source pad
C <sub>iss</sub>	Input Capacitance	—	1200	—	pF	V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance	—	570	—		V <sub>DS</sub> = -25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	81	—		f = 1.0MHz

### Source-Drain Diode Ratings and Characteristics

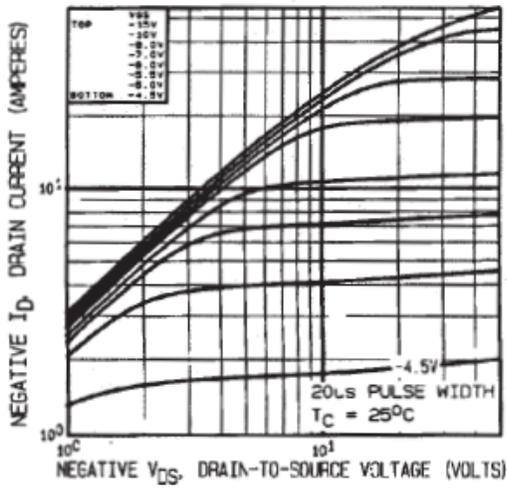
Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	-11	A	
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	-44		
V <sub>SD</sub>	Diode Forward Voltage	—	—	-5.0	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = -11A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	—	440	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = -11A, V <sub>DD</sub> ≤ -30V
Q <sub>rr</sub>	Reverse Recovery Charge	—	—	7.2	μC	di/dt = -100A/μs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

### Thermal Resistance

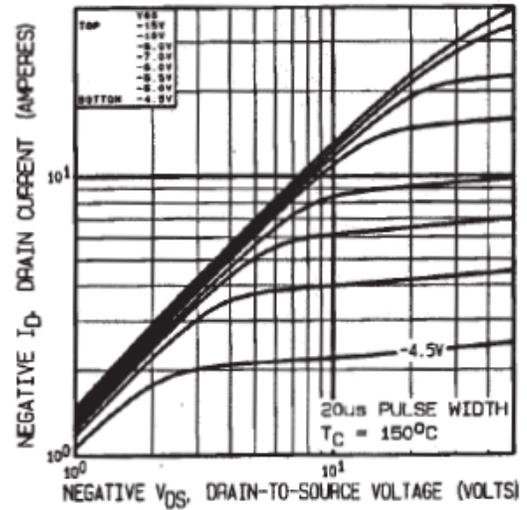
Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R <sub>θJC</sub>	Junction-to-Case	—	—	1.0	°C/W	Soldered to a copper-clad PC board
R <sub>θJ-PCB</sub>	Junction to PC Board	—	4.0	—		

### Footnotes:

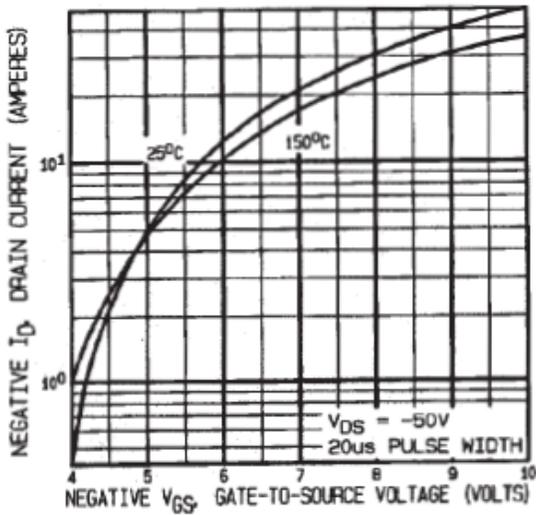
- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② V<sub>DD</sub> = -50V, starting T<sub>J</sub> = 25°C, L = 8.3mH, Peak I<sub>L</sub> = -11A, V<sub>GS</sub> = -10V.
- ③ I<sub>SD</sub> ≤ -11A, di/dt ≤ -150A/μs, V<sub>DD</sub> = -200V, T<sub>J</sub> ≤ 150°C.
- ④ Pulse width ≤ 300 μs; Duty Cycle ≤ 2%



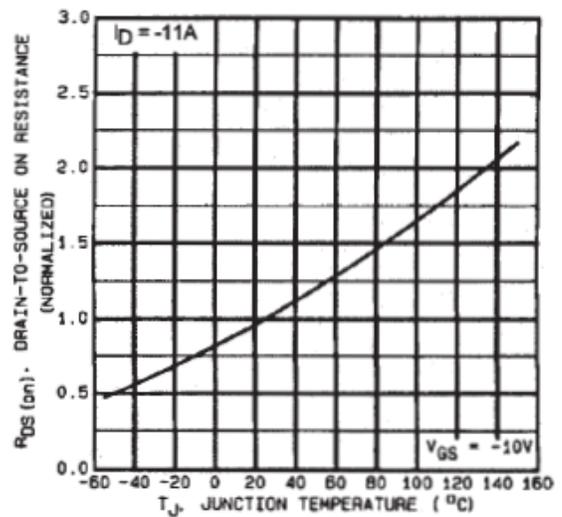
**Fig 1.** Typical Output Characteristics



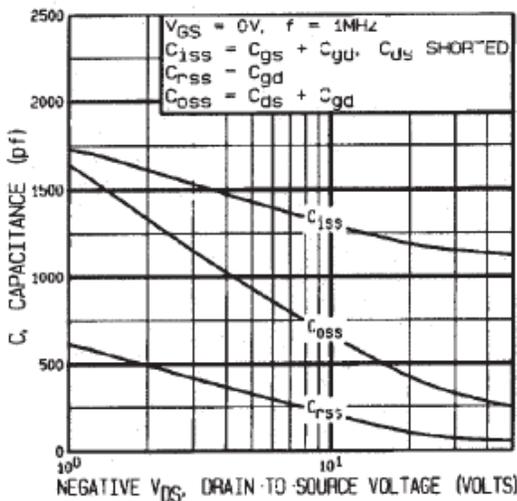
**Fig 2.** Typical Output Characteristics



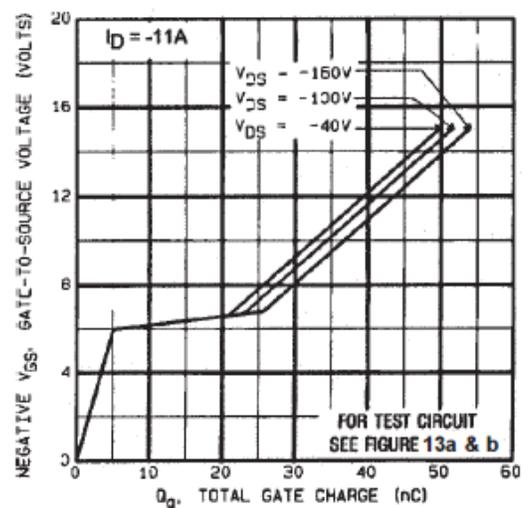
**Fig 3.** Typical Transfer Characteristics



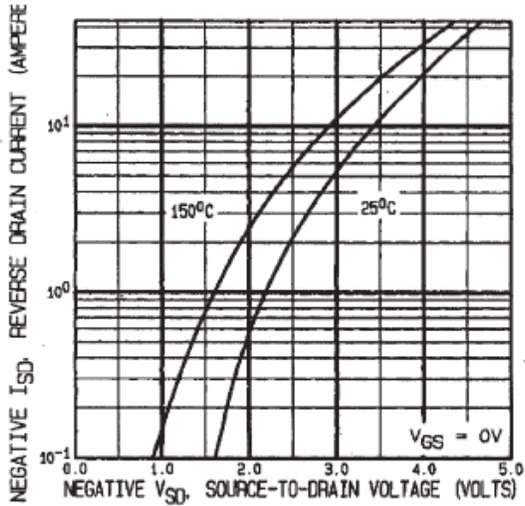
**Fig 4.** Normalized On-Resistance Vs. Temperature



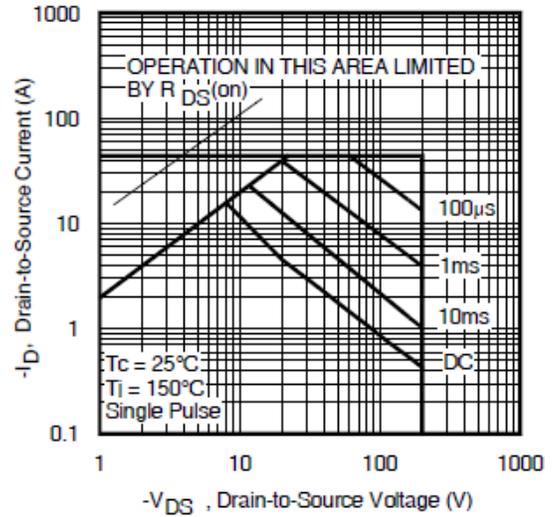
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



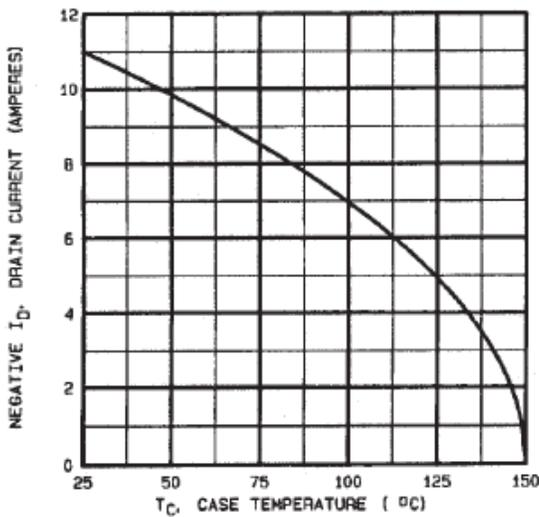
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



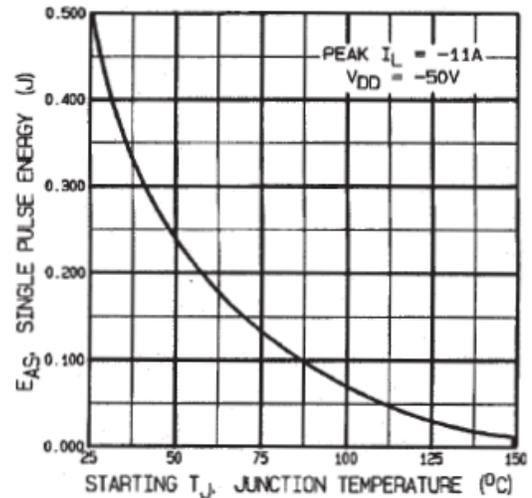
**Fig 7.** Typical Source-Drain Diode Forward Voltage



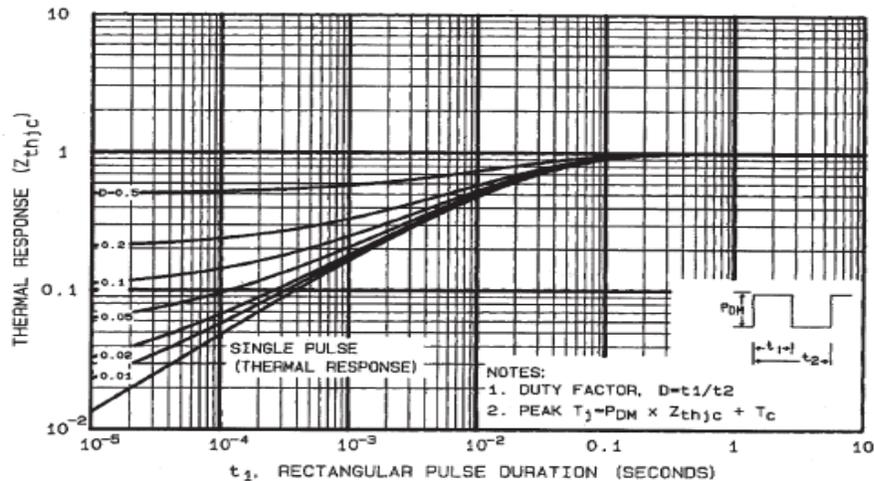
**Fig 8.** Maximum Safe Operating Area



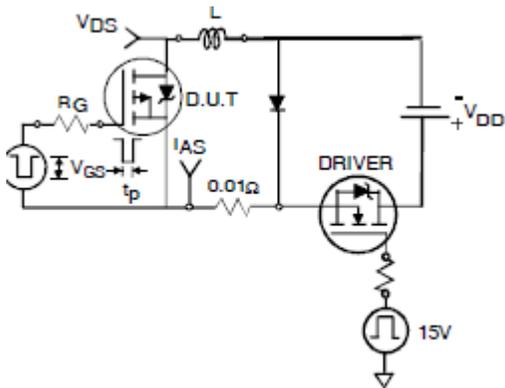
**Fig 9.** Maximum Drain Current Vs. Case Temperature



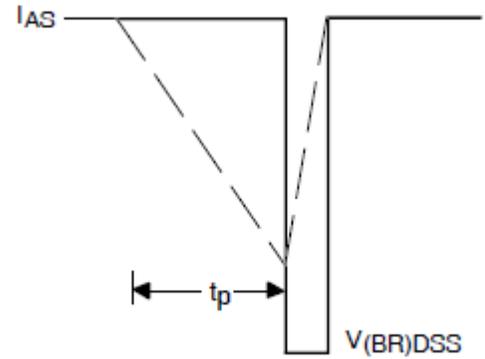
**Fig 10.** Maximum Avalanche Energy Vs. Drain Current



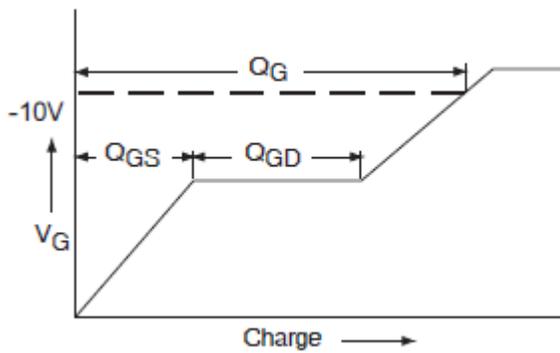
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



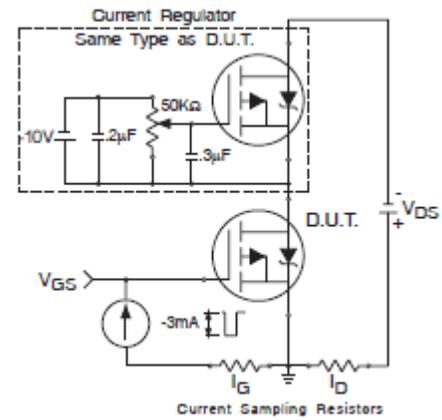
**Fig 12a.** Unclamped Inductive Test Circuit



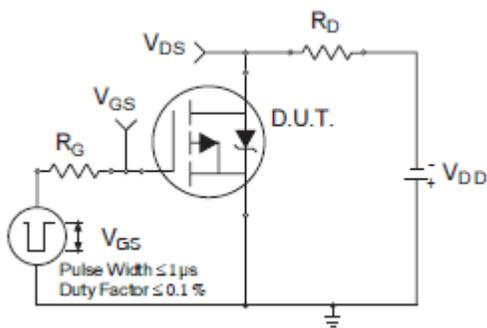
**Fig 12b.** Unclamped Inductive Waveforms



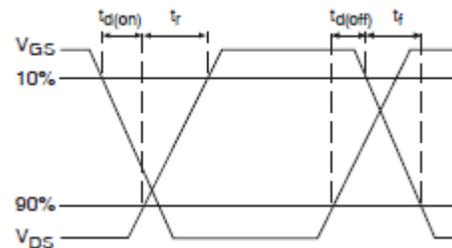
**Fig 13a.** Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit



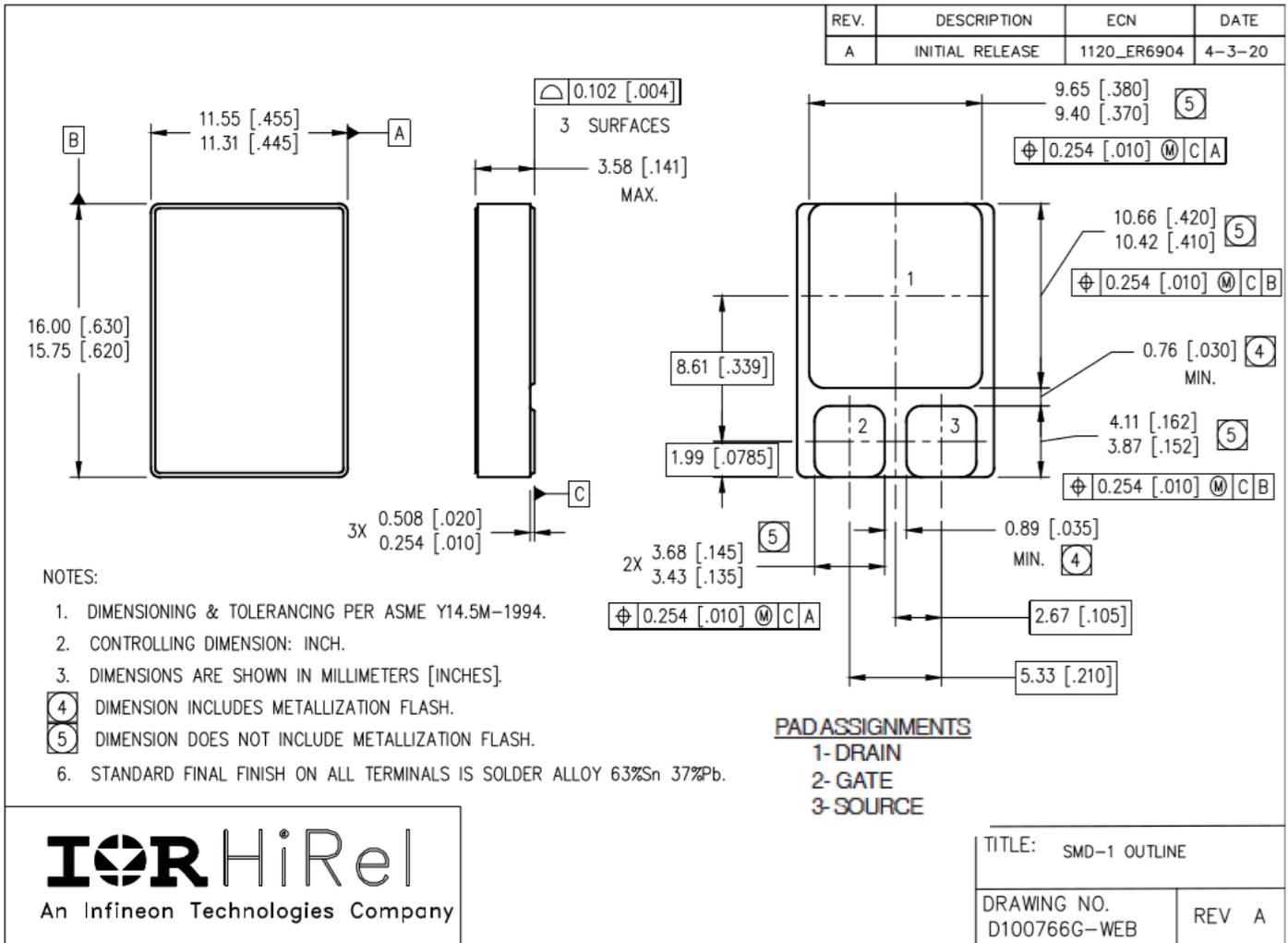
**Fig 14a.** Switching Time Test Circuit



**Fig 14b.** Switching Time Waveforms

Note: For the most updated package outline, please see the website: [SMD-1](#)

**Case Outline and Dimensions - SMD-1**



### **IMPORTANT NOTICE**

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